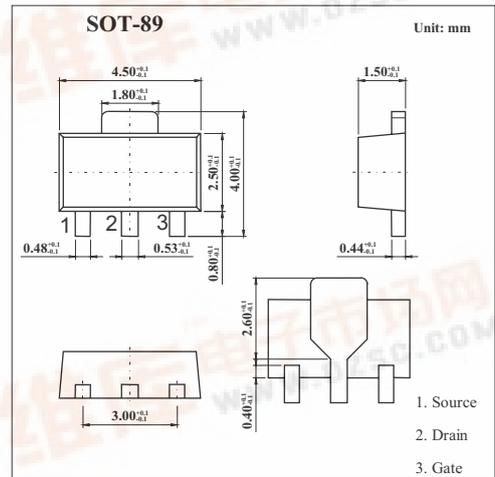
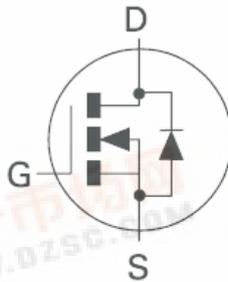


SMD Type Transistors

250V N-Channel Enhancement Mode MOSFET  
KVN4525Z

■ Features

- High voltage
- Low on-resistance
- Fast switching speed
- Low gate drive
- Low threshold
- SOT89 package



■ Absolute Maximum Ratings Ta = 25°C

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V <sub>DSS</sub>	250	V
Gate Source Voltage	V <sub>GS</sub>	±40	V
Continuous Drain Current (V <sub>GS</sub> =10V; T <sub>A</sub> =25°C)*1	I <sub>D</sub>	240	mA
	I <sub>D</sub>	192	mA
Pulsed Drain Current *3	I <sub>DM</sub>	1.44	A
Continuous Source Current (Body Diode)	I <sub>S</sub>	1.1	A
Pulsed Source Current (Body Diode)	I <sub>SM</sub>	1.44	A
Power Dissipation at T <sub>A</sub> =25°C *1	P <sub>D</sub>	1.2	W
Linear Derating Factor		9.6	mW/°C
Operating and Storage Temperature Range	T <sub>J</sub> ; T <sub>stg</sub>	-55 to +150	°C
Junction to Ambient *1	R <sub>θJA</sub>	103	°C/W
Junction to Ambient*2	R <sub>θJA</sub>	50	°C/W

\*1 For a device surface mounted on 25mm X 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions

\*2 For a device surface mounted on FR4 PCB measured at t ≤ 5 secs.

\*3 Repetitive rating - pulse width limited by maximum junction temperature. Refer to Transient Thermal Impedance graph.



## KVN4525Z

## ■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$I_D=1mA, V_{GS}=0V$	250	285		V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=250V, V_{GS}=0V$		35	500	nA
Gate-Body Leakage	$I_{GSS}$	$V_{GS}=\pm 40V, V_{DS}=0V$		$\pm 1$	$\pm 100$	nA
Gate-Source Threshold Voltage	$V_{GS(th)}$	$I_D=1mA, V_{DS}=V_{GS}$	0.8	1.4	1.8	V
Static Drain-Source On-State Resistance *1	$R_{DS(on)}$	$V_{GS}=10V, I_D=500mA$		5.6	8.5	$\Omega$
		$V_{GS}=4.5V, I_D=360mA$		5.9	9.0	$\Omega$
		$V_{GS}=2.4V, I_D=20mA$		6.4	9.5	$\Omega$
Forward Transconductance *3	$g_{fs}$	$V_{DS}=10V, I_D=0.3A$	0.3	475		ms
Input Capacitance	$C_{iss}$	$V_{DS}=25V, V_{GS}=0V, f=1MHz$		72		pF
Output Capacitance	$C_{oss}$			11		pF
Reverse Transfer Capacitance	$C_{rss}$			3.6		pF
Turn-On Delay Time	$t_{d(on)}$	$V_{DD}=50V, I_D=-200mA$		1.25		ns
Rise Time	$t_r$	$R_G=6.0\Omega, R_D=4.4\Omega$ *2,3		1.70		ns
Turn-Off Delay Time	$t_{d(off)}$			11.40		ns
Fall Time	$t_f$			3.5		ns
Total Gate Charge	$Q_g$	$V_{DS}=25V, V_{GS}=10V, I_D=360mA$ *2,3		2.6	3.65	nC
Gate-Source Charge	$Q_{gs}$			0.2	0.28	nC
Gate Drain Charge	$Q_{gd}$			0.5	0.70	nC
Diode Forward Voltage *1	$V_{SD}$	$T_j=25^\circ C, I_S=360mA, V_{GS}=0V$			0.97	V
Reverse Recovery Time *3	$t_{rr}$	$T_j=25^\circ C, I_F=360mA,$		186	260	ns
Reverse Recovery Charge *3	$Q_{rr}$	$di/dt=100A/\mu s$		34	48	nC

\*1 Measured under pulsed conditions. Width=300  $\mu$  s. Duty cycle  $\leq$  2% .

\*2 Switching characteristics are independent of operating junction temperature.

\*3 For design aid only, not subject to production testing.

## ■ Marking

Marking	N52
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